

# Abstracts

## LRM Probe-Tip Calibrations Using Nonideal Standards

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*D.F. Williams and R.B. Marks. "LRM Probe-Tip Calibrations Using Nonideal Standards." 1995 Transactions on Microwave Theory and Techniques 43.2 (Feb. 1995 [T-MTT]): 466-469.*

The line-reflect-match calibration is enhanced to accommodate imperfect match standards and lossy lines typical of monolithic microwave integrated circuits. We characterize the match and line standards using an additional line standard of moderate length. The new method provides a practical means of obtaining accurate, wideband calibrations with compact standard sets. Without the enhancement, calibration errors due to imperfections in typical standards can be severe.

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